

Notic of Referenc s Cited

	$\overline{\mathcal{E}}$	
Application/Control N	o. Applicant(s)/Pa	atent Under
09/657,506	Reexamination SON ET AL.	1
Examiner	Art Unit	
David Y. Chung	2871	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,088,079	07-2000	Kameyama et al.	349/185
	В	US-5,691,789	11-1997	Li et al.	349/98
	С	US-6,377,325	04-2002	Faris et al.	349/98
	D	US-6,433,853	08-2002	Kameyama et al.	349/176
	E	US-5,999,243	12-1999	Kameyama et al.	349/185
	F	US-6,016,177	01-2000	Motomura et al.	349/98
	G	US-6,342,934	01-2002	Kameyama et al.	349/98
	н	US-6,103,323	08-2000	Motomura et al.	428/1.3
	1	US-6,166,790	12-2000	Kameyama et al.	349/96
	J	US-6,339,501	01-2002	Kameyama et al.	359/485
	к	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

	HONE ATEN BOOMENTO				
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U				
	V	·			
	w				
	Х				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.